	Application No.	Applicant(s)
Notice of Allowability	10/043,468 Examiner	FARNWORTH, WARREN M. Art Unit
	Khiem D Nguyen	2823
The MAILING DATE of this communication claims being allowable, PROSECUTION ON THE ME rewith (or previously mailed), a Notice of Allowance (POTICE OF ALLOWABILITY IS NOT A GRANT OF PATHE Office or upon petition by the applicant. See 37 CF	RITS IS (OR REMAINS) CLOSED in TOL-85) or other appropriate community of the RIGHTS. This application is su	this application. If not included nication will be mailed in due course. THI
\boxtimes This communication is responsive to <u>12/08/2003</u> .		
The allowed claim(s) is/are <u>1-30</u> .		
The drawings filed on <u>10 January 2002</u> are accept	-	
Acknowledgment is made of a claim for foreign pria) ☐ All b) ☐ Some* c) ☐ None of the:		(f).
1. Certified copies of the priority docume	nts have been received.	•
2. Certified copies of the priority docume	nts have been received in Application	n No.
3. Copies of the certified copies of the pr		
International Bureau (PCT Rule 17.		3 11
* Certified copies not received:	,	
Acknowledgment is made of a claim for domestic p	priority under 35 U.S.C. § 119(e) (to a	provisional application).
(a) The translation of the foreign language prov		
Acknowledgment is made of a claim for domestic p		
low. Failure to timely comply will result in ABANDONM A SUBSTITUTE OATH OR DECLARATION must IF TORMAL PATENT APPLICATION (PTO-152) which gives	be submitted. Note the attached EXA	MINER'S AMENDMENT or NOTICE OF
CORRECTED DRAWINGS must be submitted.		
(a) ☐ including changes required by the Notice of D	raftsperson's Patent Drawing Review	(PTO-948) attached
1) hereto or 2) to Paper No		
(b) including changes required by the proposed d	rawing correction filed, which	has been approved by the Examiner.
(c) including changes required by the attached Ex		
Identifying indicia such as the application number (see 3 each sheet.	7 CFR 1.84(c)) should be written on the	drawings in the front (not the back) of
:		
DEPOSIT OF and/or INFORMATION about the ached Examiner's comment regarding REQUIREMENT	e deposit of BIOLOGICAL MATE	RIAL must be submitted. Note the AL MATERIAL.
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ached Examiner's comment regarding REQUIREMENT	e deposit of BIOLOGICAL MATE	RIAL must be submitted. Note the AL MATERIAL.
DEPOSIT OF and/or INFORMATION about the ached Examiner's comment regarding REQUIREMENT achm nt(s) Notice of References Cited (PTO-892) Notice of Draftperson's Patent Drawing Review (PTO Information Disclosure Statements (PTO-1449), Paper	FOR THE DEPOSIT OF BIOLOGIC 2 Notice of 4 Interview	RIAL must be submitted. Note the AL MATERIAL. Informal Patent Application (PTO-152) Summary (PTO-413), Paper No 's Amendment/Comment

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DETAILED ACTION

Terminal Disclaimer

The terminal disclaimer filed on 12/08/2003 disclaiming the terminal portion of any patent granted on this application which would extend beyond the expiration date of the full statutory term defined in 35 U.S.C. 154 to 156 and 173, as presently shortened by any terminal disclaimer, of prior Patent No. 5,933,713 and Patent No. 6,204,095 has been reviewed and is accepted. The terminal disclaimer has been recorded.

Allowable Subject Matter

Claims 1-30 are allowed..

Reasons For Allowance

The following is a statement of reasons for the indication of allowable subject matter: The prior art taken alone or in combination neither discloses nor makes obvious the instant process of claims as a whole. Specifically, the prior art of record, Akagawa (U.S. Patent 5,677,576) discloses a method for forming a semiconductor wafer (FIG. 1: 32) having an active surface, the active surface having bond pads (FIG. 1: 36) thereon, the method comprising: forming conductive traces (FIG. 1: 40) over the active surface, each of the conductive traces having a first end, a second end, a top surface, and a bottom surface wherein the bottom surface of the first end of each conductive trace being in contact with at least one of the bond pads (col. 3, lines 10-39), forming a conductive bump (FIG. 1: 46) on the top surface at the second end of the conductive traces wherein the conductive bump having a top portion transverse to the top surface of the conductive traces (col. 3, lines 58-60, and forming a layer of encapsulation material (FIG. 1: 42) to

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cover the active surface of the semiconductor wafer and to surround the conductive bump (col. 3, lines 47-48) but fails to teach or suggest the Applicant's steps of planarizing the top portion of the conductive bump, forming a layer of encapsulation material to cover the active surface of the semiconductor wafer and to surround the planarized conductive bump, and reforming the conductive bump to a preplanarized shape extending above the layer and away from at least portion of the encapsulation material adjacent to the conductive bump as recited in the amended independent claims.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Khiem D Nguyen whose telephone number is (703) 306-0210. The examiner can normally be reached on Monday-Friday (8:00 AM - 5:00 PM).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Olik Chaudhuri can be reached on (703) 306-2794. The fax phone numbers for the organization where this application or proceeding is assigned are (703) 305-3432 for regular communications and (703) 305-3432 for After Final communications.

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Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

K.N.

December 22, 2003

W. David Coleman-Primary Examiner